PCN Number:			2	20230731002.2						e:	August 02, 2023	
Title	::	Qualifica	tion of	of new BOM for select package Devices								
Customer Contact:				hange Mai	nagei	ment team	Dept:	Qι	Quality Services			
Proposed 1 st Ship Date							Sample requests accepted until: Aug 31, 2			g 31, 2023*		
*Sai	mple r	equests re	eceived	d after Aug 31, 2023 will not be supported.								
Cha	nge T	ype:										
	Asse	mbly Site				Design			Wafer Bump Material			
	Asse	mbly Proce	ess			Data Shee			Wafer Bump Process		o Process	
\boxtimes	Asse	mbly Mate	rials			Part number change			Wafer Fab Site			
☐ Mechanical Specific				ion		Test Site			Wafer Fab Material			
		ing/Shippi				Test Process			Wafer Fab Process			
		<u> </u>	<u> </u>	- J		1 1 2 2 1 1 2 2 2 2			Wafer F			
						PCN Det	ails					
Des	criptio	on of Cha	nge:									
liste	Texas Instruments Incorporated is announcing the qualification of new material set for the devices listed in the "Product Affected" Section. Devices will remain at current location. Material Difference:											
				Current		Proposed						
		· · ·				-						
	Lead f	inisn		NiPdAu		Matt	e Sn					
Upon expiration of this PCN, TI will combine lead free solutions in a single <u>standard part</u> <u>number</u> , for example; <u>TPS25850QRPQRQ1</u> – can ship with both Matte Sn and NiPdAu.												
Example: - Customer order for 7500 units of TPS25850QRPQRQ1 with 2500 units SPQ (Standard Pack Quantity per Reel). - TI can satisfy the above order in one of the following ways. I. 3 Reels of NiPdAu finish. II. 3 Reels of Matte Sn finish III. 2 Reels of Matte Sn and 1 reel of NiPdAu finish. IV. 2 Reels of NiPdAu and 1 reel of Matte Sn finish.												
Reason for Change:												
Cont	inuity	of supply.	•									
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):												
None												
Impact on Environmental Ratings												
Checked boxes indicate the status of environmental ratings following implementation of this change. If below boxes are checked, there are no changes to the associated environmental ratings.												
RoHS				RE	ACH	1	Green St		IEC	62474		
No Change				No Change			No Change			No Change		

Changes to product identification resulting from this PCN:

Sample product shipping label (not actual product label)

G4 = NiPdAuG3 = Matte Sn

TEXAS INSTRUMENTS MADE IN: Malaysia 2DC: 2Q:

MSL 2 /260C/1 YEAR SEAL DT

03/29/04

(1P) SN74LS07NSR

31T)LOT: 3959047MLA 4W) TKY(1T) 7523483SI2

(2P) REV: (V) 0033317 (20L) CSO: SHE (21L) CCO:USA (22L) ASO: MLA (23L) ACO: MYS

MSL 1 /235C/UNLIM OPT: ITEM:

(L)T0:1750 LBL: 5A

Product Affected:

PTPS25850A0QRPQTQ1	TPS25854QRPQRQ1	TPS25860QRPQRQ1	TPS25868QRPQRQ1
TPS25850QRPQRQ1	TPS25855QRPQRQ1	TPS25862QRPQRQ1	TPS25869QRPQRQ1
TPS25851QRPQRQ1	TPS25858QRPQRQ1	TPS25864QRPQRQ1	TPS552882QRPMRQ1
TPS25852QRPQRQ1	TPS25859QRPQRQ1	TPS25865QRPQRQ1	TPS55288QRPMRQ1

Qualification Report Automotive New Product Qualification Summary (As per AEC-Q100 and JEDEC Guidelines)

Approve Date 25-JuL-2023

Product Attributes

Attributes	Qual Device:	Qual Device:		
Attributes	TPS552882QRPMRQ1	TPS25858QRPQRQ1		
Automotive Grade Level	Grade 1	Grade 1		
Operating Temp Range (C)	-40 to 125	-40 to 125		
Product Function	Power Management	Power Management		
Wafer Fab Supplier	RFAB	RFAB		
Assembly Site	CDAT	CDAT		
Package Group	QFN	QFN		
Package Designator	RPM	RPQ		
Pin Count	26	25		

QBS: Qual By Similarity

Qual Device TPS552882QRPMRQ1 is qualified at MSL2 260C Qual Device TPS25858QRPQRQ1 is qualified at MSL2 260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	#	Test Spec	Min Lot Qty	SS / Lot	Test Name	Condition	Duration	Qual Device: TPS552882QRPMRQ1	Qual Device: TPS25858QRPQRQ1	
Test Group	Test Group A - Accelerated Environment Stress Tests									
PC	A1	JEDEC J-STD-020 JESD22-A113	3	77	Preconditioning	MSL2 260C	-	3/462/0	3/462/0	
AC/UHAST	A3	JEDEC JESD22- A102/JEDEC JESD22- A118	3	77	Autoclave	121C/15psig	96 Hours	3/231/0	3/231/0	
тс	A4	JEDEC JESD22-A104 and Appendix 3	3	77	Temperature Cycle	-55C/150C	1000 Cycles	3/231/0	3/231/0	
Test Group	Test Group B - Accelerated Lifetime Simulation Tests									
Test Group	C - Pack	age Assembly Integrity Tes	ts							
SD	C3	JEDEC J-STD-002	1	15	PB-Free Solderability	>95% Lead Coverage	-	1/15/0	1/15/0	
Test Group	Test Group D - Die Fabrication Reliability Tests									
EM	D1	JESD61	-	-	Electromigration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
TDDB	D2	JESD35	-	-	Time Dependent Dielectric Breakdown	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
нсі	D3	JESD60 & 28	-	-	Hot Carrier Injection	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
NBTI	D4	-	-	-	Negative Bias Temperature Instability	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	
SM	D5	-	-	-	Stress Migration	-	-	Completed Per Process Technology Requirements	Completed Per Process Technology Requirements	

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

The following are equivalent HTOL options based on an activation energy of 0.7eV:125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

The following are equivalent HTSL options based on an activation energy of 0.7eV:150C/1k Hours, and 170C/420 Hours

The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles

Ambient Operating Temperature by Automotive Grade Level:

Grade 0 (or E): -40C to +150C Grade 1 (or Q): -40C to +125C Grade 2 (or T): -40C to +105C Grade 3 (or I): -40C to +85C

E1 (TEST): Electrical test temperatures of Qual samples (High temperature according to Grade level):

Room/Hot/Cold: HTOL, ED

Room/Hot: THB / HAST, TC / PTC, HTSL, ELFR, ESD & LU

Room: AC/uHAST

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/

ZVEI ID: SEM-PA-05

For questions regarding this notice, e-mails can be sent to the Change Management team or your local Field Sales Representative.

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